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(54) **LOW POWER CLOCK GATED FLIP-FLOPS**

(71) Applicant: **Texas Instruments Incorporated,**  
Dallas, TX (US)

(72) Inventors: **Girishankar Gurumurthy,** Bangalore  
(IN); **Mahesh Ramdas Vasishta,**  
Bangalore, IN (US)

(73) Assignee: **TEXAS INSTRUMENTS**  
**INCORPORATED,** Dallas, TX (US)

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**H03K 3/3562** (2006.01)  
**H03K 3/012** (2006.01)

(52) **U.S. Cl.**  
CPC ..... **H03K 3/35625** (2013.01); **H03K 3/012**  
(2013.01)

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None

See application file for complete search history.

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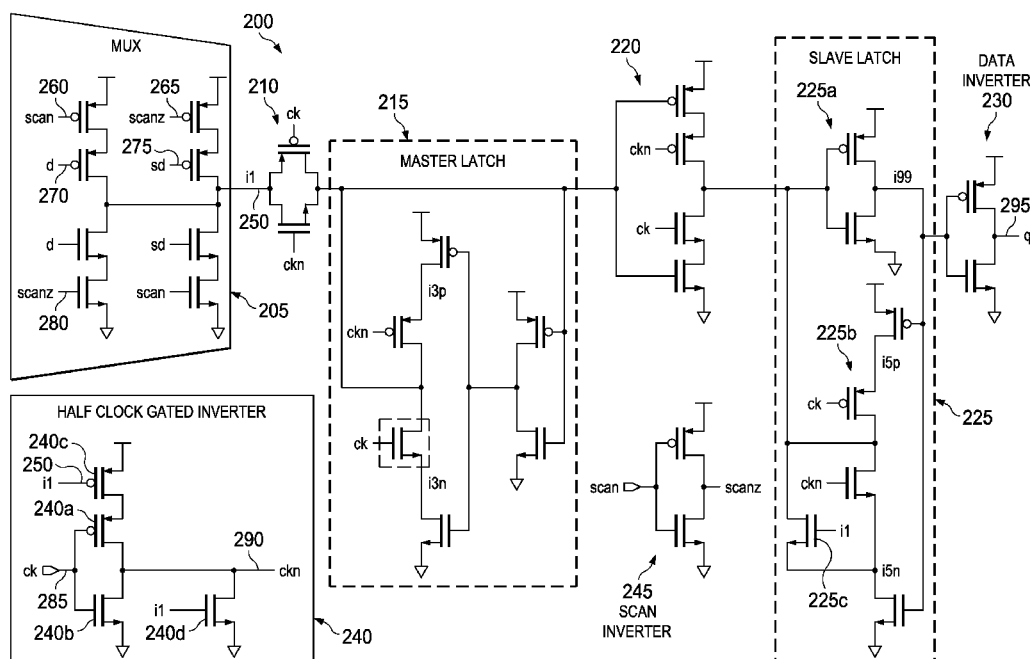
*Primary Examiner* — Long Nguyen

(74) *Attorney, Agent, or Firm* — John R. Pessetto; Charles A.  
Brill; Frank D. Cimino

(57) **ABSTRACT**

A flip-flop that includes a multiplexer configured to generate a multiplexer output. The multiplexer output is generated in response to an input and a scan enable, and is given to a transmission gate. A master latch is coupled to the transmission gate and to a tri-state inverter. The master latch is configured to receive an output of the transmission gate. A slave latch is configured to receive an output of the tri-state inverter and the multiplexer output. A data inverter is coupled to the slave latch. The data inverter is configured to generate a flip-flop output. A half clock gating inverter is configured to generate an inverted clock input in response to a clock input and the multiplexer output.

**10 Claims, 6 Drawing Sheets**



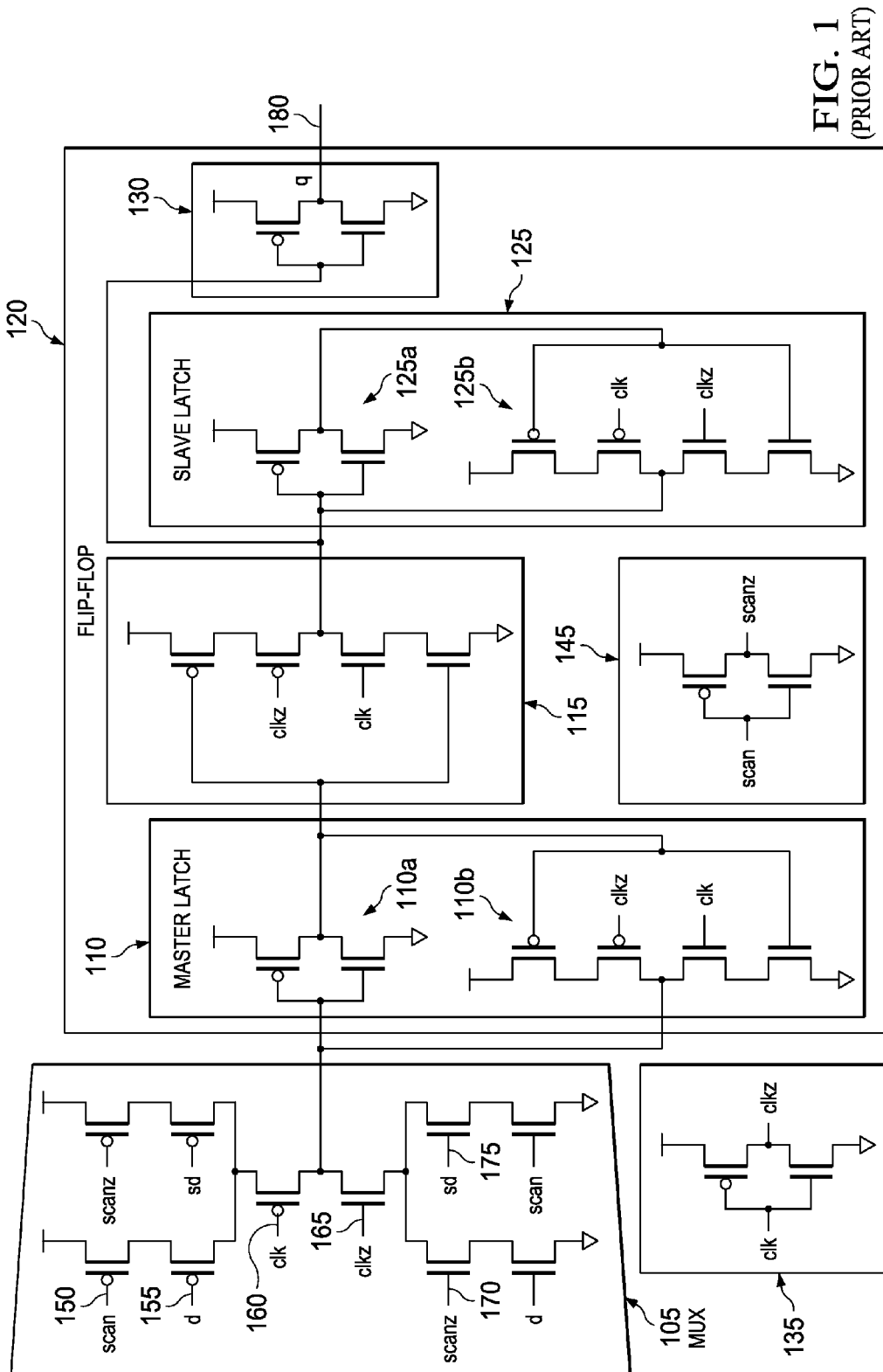
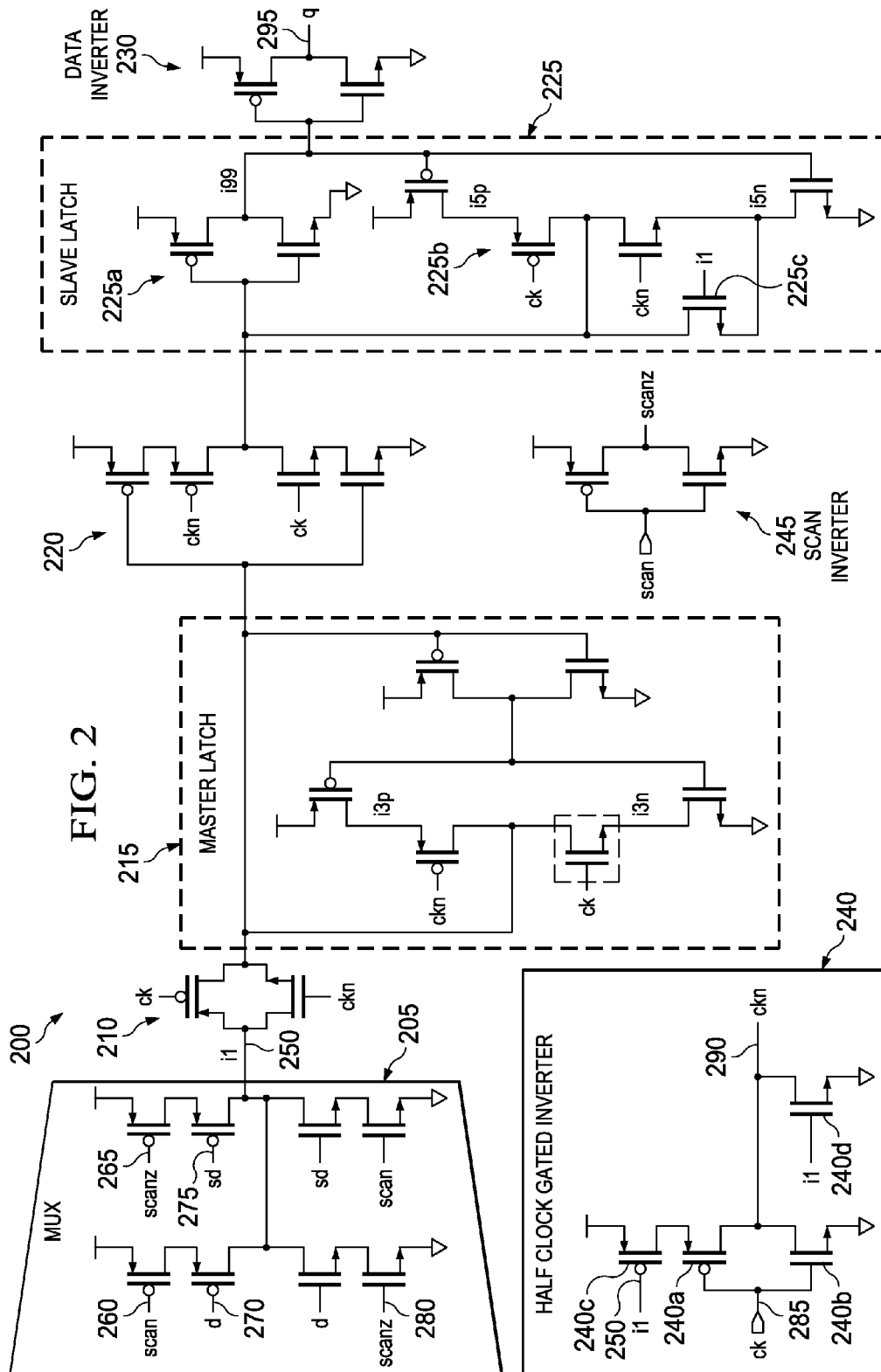
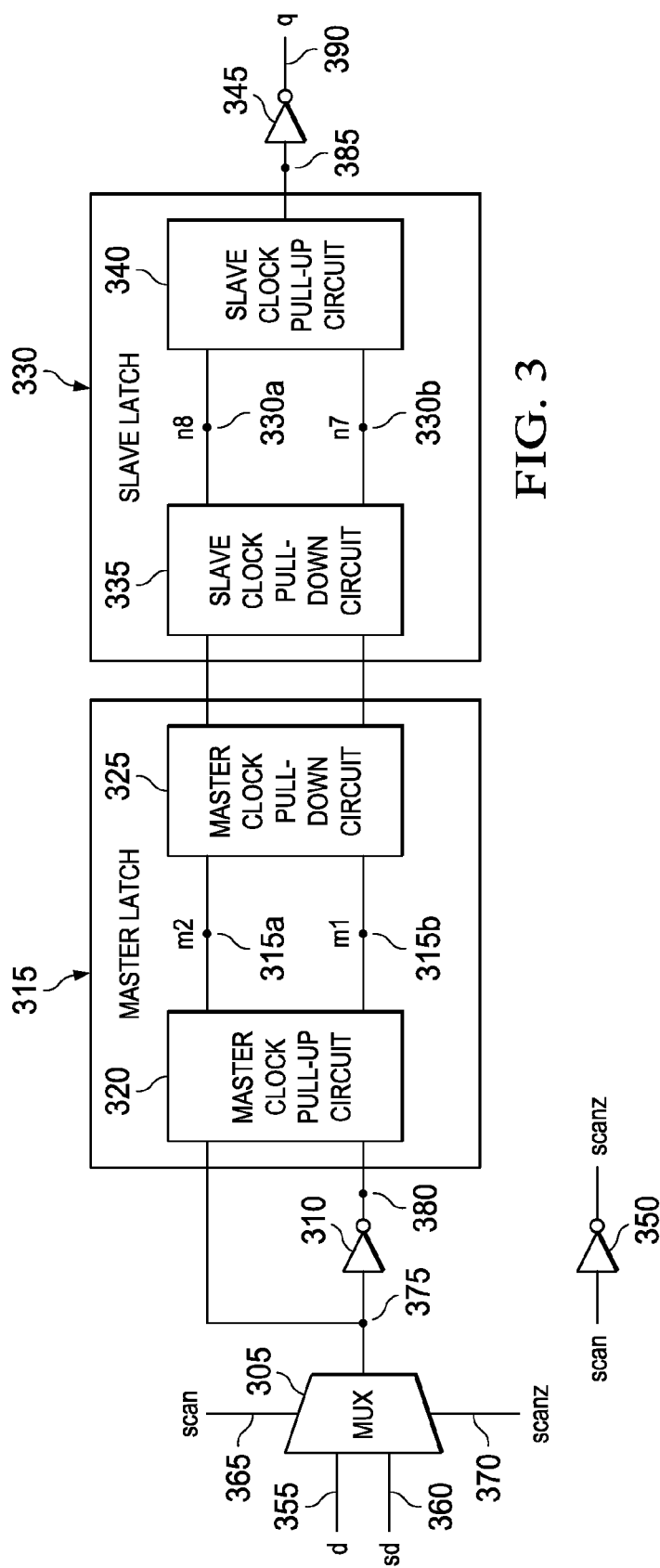


FIG. 1  
(PRIOR ART)





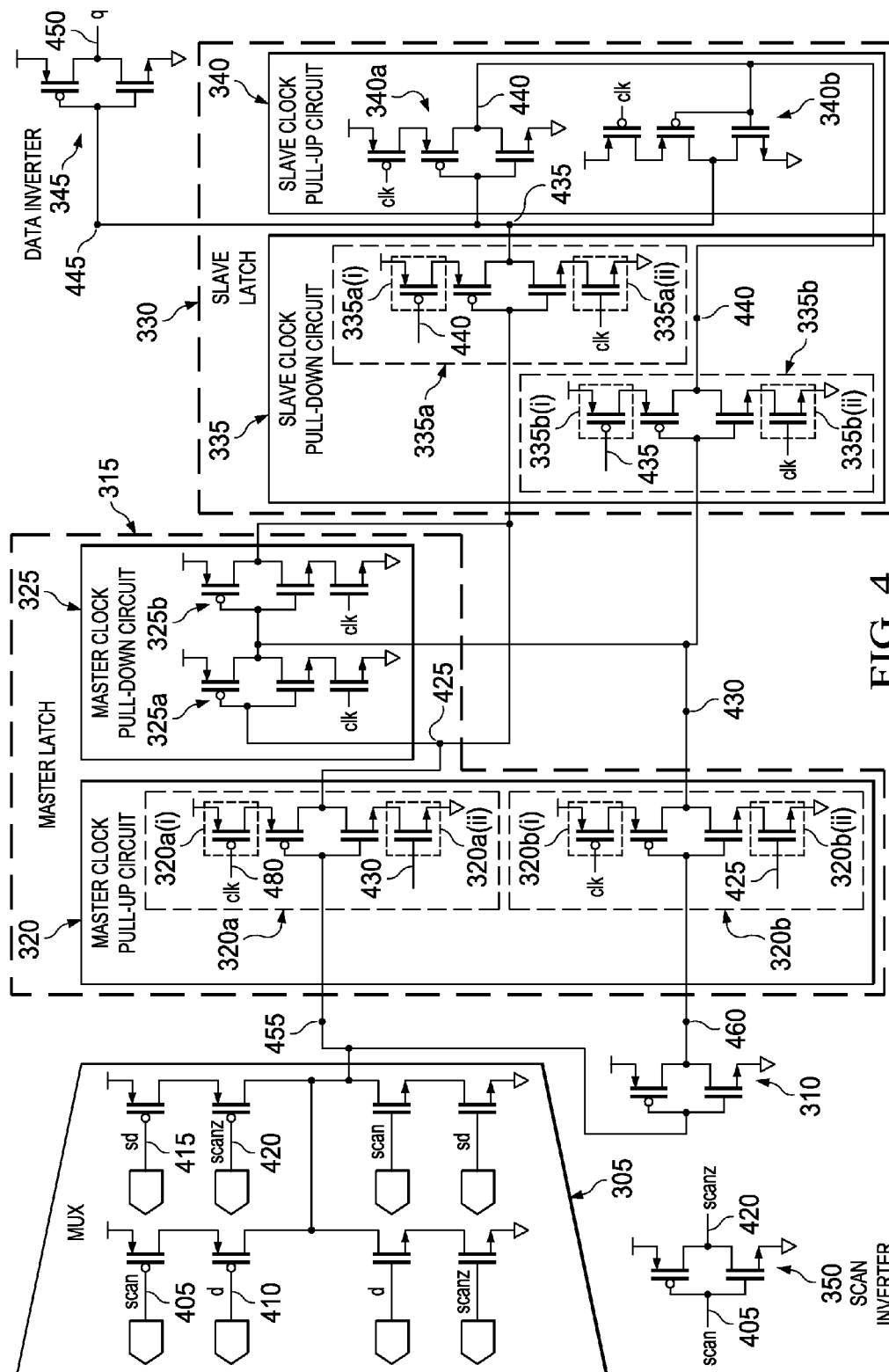
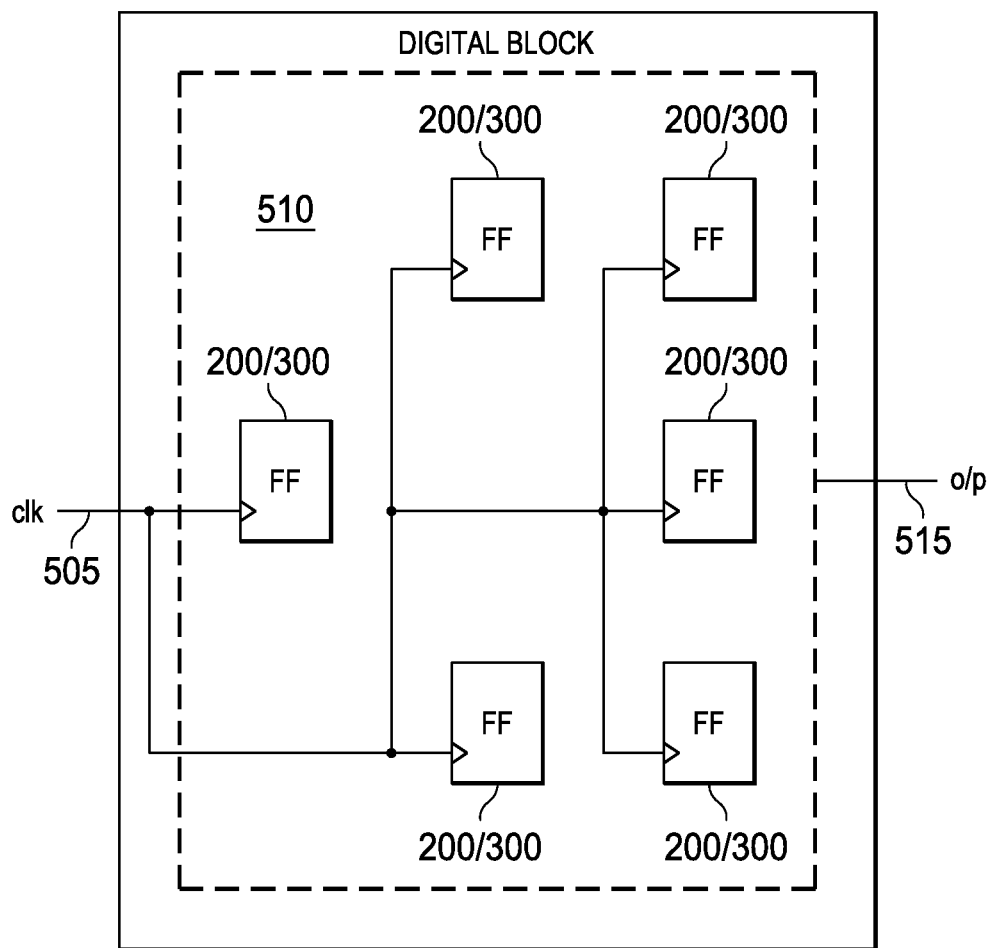


FIG. 4

FIG. 5



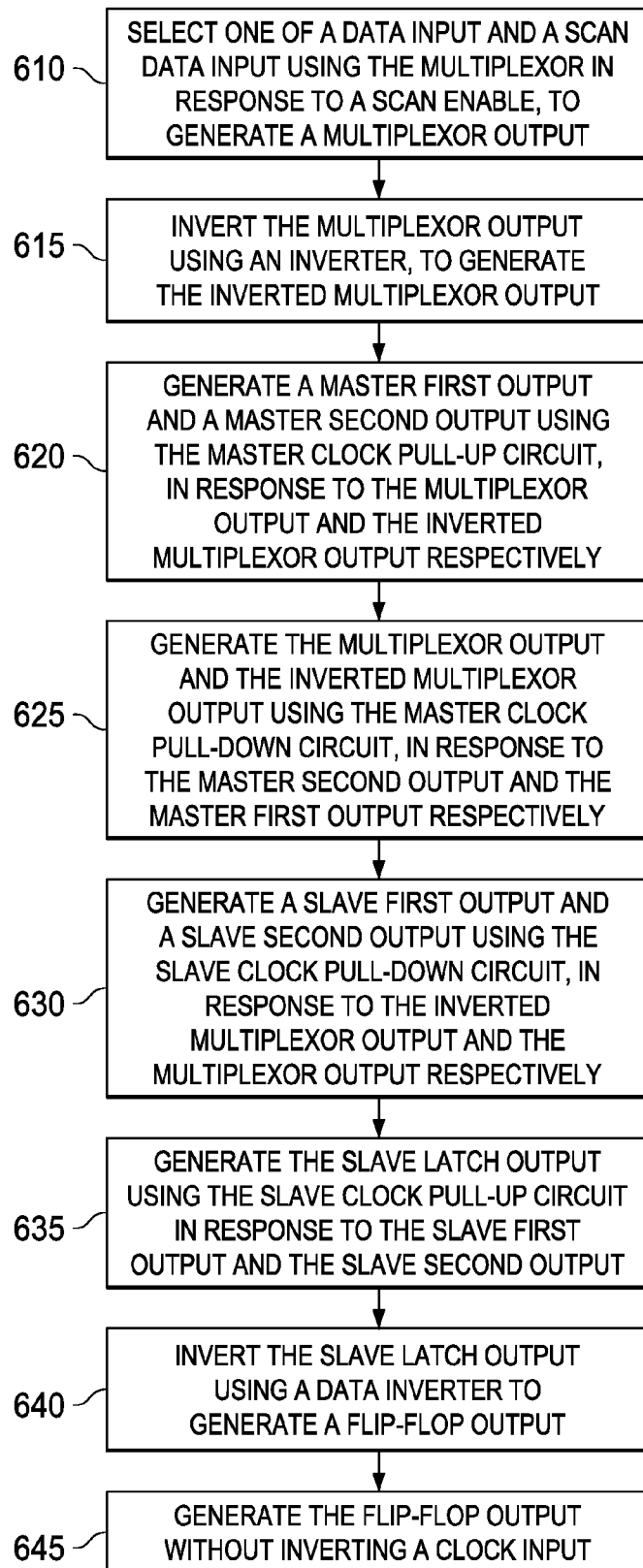


FIG. 6

**LOW POWER CLOCK GATED FLIP-FLOPS****CROSS REFERENCE TO RELATED APPLICATIONS**

This application claims priority from U.S. provisional patent application No. 61/875,990 filed on Sep. 10, 2013, which is hereby incorporated by reference in its entirety.

**TECHNICAL FIELD**

Embodiments of the disclosure relate to low power clock gated flip-flops in an integrated circuit.

**BACKGROUND**

In modern integrated circuits (ICs), the flip-flops contribute to a substantial portion of any circuit design's power consumption. A comparison of the power consumption by the various units in an IC is as follows; logic implementation 29%, flip flops 27%, RAM 18%, clock tree 16% and the integrated clock gating (ICG) consumes 10% of the total power in a typical design. Therefore in an IC, the significant power consumption is due to tedious synchronization of the various clock phases and routing of the clock signals. The majority of power inside a flip flop is consumed by the transistors receiving the clock input, since the data activity factors are typically much lower. Irrespective of whether the data changes every cycle or not, the transistors receiving the clock input keep switching at every clock cycle. Thus, it is apparent that with reduced transistor switching, the power consumed by the flip-flop can also be reduced. Further, constant toggling of the clock input causes a significant amount of gate capacitances. It is apparent that with the reduction in the number gate capacitances, a considerable amount of power consumed by the flip-flop in the IC can be reduced.

**SUMMARY**

This Summary is provided to comply with 37 C.F.R. §1.73, requiring a summary of the invention briefly indicating the nature and substance of the invention. It is submitted with the understanding that it will not be used to interpret or limit the scope or meaning of the claims.

An example embodiment provides a flip-flop. The flip-flop includes a multiplexer configured to generate a multiplexer output. The multiplexer output is generated in response to an input and a scan enable, and is given to a transmission gate. A master latch is configured to receive an output of the transmission gate. A tri-state inverter is configured to receive an output of the master latch. A slave latch is configured to receive an output of the tri-state inverter and the multiplexer output. Further, a data inverter is coupled to the slave latch. The data inverter is configured to generate a flip-flop output. A half clock gating inverter is configured to generate an inverted clock input in response to a clock input and the multiplexer output.

Another example embodiment provides an apparatus. The apparatus includes a clock input and a plurality of flip-flops. The plurality of flip-flops is configured to receive the clock input. Each of the flip-flops includes a multiplexer configured to generate a multiplexer output. The multiplexer output is generated in response to an input and a scan enable, and is given to a transmission gate. A master latch is configured to receive an output of the transmission gate. A tri-state inverter is configured to receive an output of the master latch. A slave latch is configured to receive an output of the tri-state inverter

and the multiplexer output. Further, a data inverter is coupled to the slave latch. The data inverter is configured to generate a flip-flop output. A half clock gating inverter is configured to generate an inverted clock input in response to a clock input and the multiplexer output. The half clock gating inverter includes a first PMOS and a first NMOS transistor, both of which are configured to receive the clock input at the gate terminal and generate the inverted clock input. A second PMOS transistor is coupled to a source of the first PMOS transistor; the second PMOS transistor is configured to be controlled by the multiplexer output. A second NMOS transistor is coupled to a node between the drains of the first PMOS transistor and the first NMOS transistor. The second NMOS transistor is configured to be controlled by the multiplexer output.

Another example embodiment provides a flip-flop. The flip-flop includes a multiplexer configured to generate a multiplexer output. An inverter is coupled to the multiplexer configured to generate an inverted multiplexer output. A master latch is configured to receive the multiplexer output and the inverted multiplexer output. The master latch includes a master clock pull-up circuit coupled to a master clock pull-down circuit. The slave latch is coupled to the master latch and is configured to receive a pair of complementary outputs from the master latch. The slave latch includes a slave clock pull-down circuit coupled to a slave clock pull-up circuit. The slave clock pull-up circuit is configured to generate a slave latch output. A data inverter is configured to generate a flip-flop output in response to the slave latch output.

Another example of an embodiment provides an apparatus. The apparatus includes a clock input and a plurality of flip-flops configured to receive the clock input. Each of the plurality of flip-flops includes a multiplexer configured to generate a multiplexer output. An inverter is coupled to the multiplexer configured to generate an inverted multiplexer output. A master latch is configured to receive the multiplexer output and the inverted multiplexer output. The master latch includes a master clock pull-up circuit coupled to a master clock pull-down circuit. The slave latch is coupled to the master latch and is configured to receive a pair of complementary outputs the master latch. The slave latch includes a slave clock pull-down circuit coupled to a slave clock pull-up circuit. The slave clock pull-up circuit is configured to generate a slave latch output. A data inverter is configured to generate a flip-flop output in response to the slave latch output. The master clock pull-up circuit and the slave clock pull-down circuit are configured such that the flip-flop output is generated without inverting the clock input.

Other aspects and example embodiments are provided in the Drawings and the Detailed Description that follows.

**BRIEF DESCRIPTION OF THE VIEWS OF DRAWINGS**

FIG. 1 illustrates a schematic of a flip-flop (prior art);

FIG. 2 illustrates a schematic of a transistor level implementation of a flip-flop according to an embodiment;

FIG. 3 illustrates a schematic of a flip-flop according to an embodiment;

FIG. 4 illustrates a schematic of a transistor level implementation of a flip-flop of FIG. 3;

FIG. 5 illustrates schematic of an apparatus using flip-flops according to an embodiment; and

FIG. 6 is a flowchart illustrating a method of generating a flip-flop output according to an embodiment.



## DETAILED DESCRIPTION OF THE EMBODIMENTS

FIG. 1 illustrates a schematic of a flip-flop 100. The flip flop 100 includes a multiplexer 105. The multiplexer 105 receives a data input D 155, a scan data input SD 175, a scan enable SCAN 150, an inverted scan enable SCANZ 170, a clock input CLK 160 and an inverted clock input CLKZ 165. The multiplexer 105 is coupled to a master latch 110. The output of the master latch 110 is received at a tri-state inverter 115. A slave latch 125 is coupled to the tri-state inverter 115. The master latch 110 and the slave latch 125 are implemented using two back-to-back inverters. The back-to-back inverters include an inverter 110a and a tri-state inverter 110b in the master latch and an inverter 125a and a tri-state inverter 125b in the slave latch. An output of the slave latch 125 is received at a data inverter 130. The data inverter 130 generates a flip-flop output 180. An inverter 135 receives the clock input CLK 160 to generate the inverted clock input CLKZ 165. An inverter 145 receives the scan enable SCAN 150 to generate an inverted scan enable SCANZ 170.

The operation of the flip-flop illustrated in FIG. 1 is explained now. The flip-flop 100 is implemented using MOS transistors. The multiplexer 105 selects either the data input D 155 or the scan data input SD 175 in response to the scan enable SCAN 150. The data input 155 or the scan data input SD 175 is stored using the master latch 110 coupled to the tri-state inverter 115 and the slave latch 125. The output of the slave latch 125 is inverted by the data inverter 130 to generate the flip-flop output Q 180. The majority of power inside the flip flop 100 is consumed by the transistors receiving the clock input 160 and the inverted clock input 165. Irrespective of whether there is a change in either the data input 155 or the scan data input 175 the transistors receiving the clock input 160 and the inverted clock input 165 switch at every clock cycle. In the flip-flop 100, the clock input 160 and the inverted clock input 165 are received at the multiplexer 105, the tri-state inverter 110b of the master latch 110, the tri-state inverter 115 and the tri-state inverter 125b of the slave latch. Therefore, there are a total of 10 transistors that receive either the clock input 160 or the inverted clock input 165. It is apparent that with reduced switching at the transistors, the power consumed by the flip-flop 100 can also be reduced. Further, the constant toggling of the clock input 160 and the inverted clock input 165 introduces a significant amount of gate coupling. With the reduction in the amount of gate coupling, a considerable amount of power consumed by the flip-flop 100 can be reduced. In addition to the power loss, if only one inverter is used to invert the clock input 160 in an IC the plurality of the flip-flops 100 must be arranged in a vector. Hence, the flip-flops 100 must be aligned with respect to the clock input 160, resulting in a power efficient design.

FIG. 2 illustrates a schematic of a transistor level implementation of a flip-flop 200, according to an embodiment. The flip-flop 200 is implemented using PMOS and NMOS transistors. The flip-flop 200 includes a multiplexer 205 which is configured to generate a multiplexer output 250. The multiplexer output 250 is generated in response to an input (data input 270 or scan data input 275) and a scan enable 260 and given to a transmission gate 210. A master latch 215 is configured to receive an output of the transmission gate 210. A tri-state inverter 220 is configured to receive an output of the master latch 215. A slave latch 225 is configured to receive an output of the tri-state inverter 220 and the multiplexer output 250. A data inverter 230 is coupled to the slave latch 225. The data inverter 230 is configured to generate a flip-flop

output 295. The flip-flop output 295 is a data output when scan enable 260 is disabled and a scan data output when scan enable 260 is enabled.

The flip-flop 200 further includes a half clock gating inverter 240. The half clock gating inverter 240 is configured to generate an inverted clock input 290 in response to a clock input 285 and the multiplexer output 250. The half clock gating inverter 240 is implemented using an inverter having a first PMOS transistor 240a and a first NMOS transistor 240b, receiving the clock input 285 to generate the inverted clock input 290. A second PMOS transistor 240c is coupled to a source of the first PMOS transistor 240a. A gate of the second PMOS transistor 240c is configured to be controlled by the multiplexer output 250. The half clock gating inverter 240 further includes a second NMOS transistor 240d coupled to a node between the drains of the first PMOS transistor 240a and the first NMOS transistor 240b. A gate of the second NMOS transistor 240d is configured to be controlled by the multiplexer output 250.

The operation of the flip-flop 200 illustrated in FIG. 2 is explained now. In the flip-flop 200, the multiplexer 205 receives the data input 270, the scan data input 275, a scan enable 260 and an inverted scan enable 265 and selects one of the data input 270 and the scan data input 275 in response to the scan enable 260. The scan enable 260 is inverted using a scan inverter 245 to generate the inverted scan enable 265. The multiplexer output 250 is received at the transmission gate 210. The multiplexer 205 generates the multiplexer output 250 which is then stored in the master latch 215 using a first plurality of back-to-back inverters. Each of the first plurality of back-to-back inverters includes an inverter coupled to a tri-state inverter. The multiplexer output 250 is then inverted using the tri-state inverter 220. The slave latch 225 coupled to the tri-state inverter 220 includes a second plurality of back-to-back connected inverters. Each of the second plurality of back-to-back connected inverters includes a first inverter 225a coupled to a second tri-state inverter 225b. The first inverter 225a of the second plurality of back-to-back connected inverters is configured to generate an output to the data inverter 230. A third NMOS transistor 225c is coupled in parallel to an NMOS transistor of the second tri-state inverter 225b. A gate of the third NMOS transistor 225c receives the multiplexer output 250 and a gate of the NMOS transistor of the second tri-state inverter 225b is configured to receive the inverted clock input 290. When the multiplexer output 250 is logic '0', the third NMOS transistor 225c of the slave latch 225 is inactivated. It is noted that the flip-flop output 295 is generated in the same manner as explained for the flip-flop 100 illustrated in FIG. 1. Further, when the multiplexer output 250 is logic '0', the half clock gating inverter 240 generates the inverted clock input 290 as the second PMOS transistor 240c is activated and the second NMOS transistor 240d is inactivated.

The flip-flop 200 is in a power save mode when the multiplexer output 250 is logic '1'. The multiplexer output 250 is logic '1' when the input (data input 270 or scan data input 275) is logic '0'. When the multiplexer output is logic '1', the second PMOS transistor 240c of the half clock gated inverter 240 is inactivated and the second NMOS transistor 240d is activated, thereby the inverted clock input 290 is tied to logic '0' irrespective of the state of the clock input 285. Further, when the clock input 285 is logic '0' the NMOS transistor of the second tri-state inverter 225b in the slave latch 225 is inactivated as the inverted clock input 290 is tied to logic '0'. The slave latch 225 stores the multiplexer output 250 using the third NMOS transistor 225c coupled in parallel to the NMOS transistor of the second tri-state inverter 225b. When

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the multiplexer output **250** is logic '1', the number of transistors that receive constantly toggling inverted clock input **290** is reduced from **10** transistors seen in flip-flop **100** to **6** transistors in flip-flop **200**. The flip-flop **200** utilizes only **3** more transistors compared to flip-flop **100**. Therefore, the flip-flop **200** is a low-area overhead solution that reduces the power consumed by the transistors that receive the inverted clock input **290**.

FIG. 3 illustrates a schematic of a flip-flop **300** according to an embodiment. The flip-flop **300** is implemented using PMOS and NMOS transistors. The flip-flop **300** includes a multiplexer **305** configured to generate a multiplexer output **375**. An inverter **310** is coupled to the multiplexer **305** configured to generate an inverted multiplexer output **380**. A master latch **315** is configured to receive the multiplexer output **375** and the inverted multiplexer output **380**. The master latch **315** includes a master clock pull-up circuit **320** coupled to a master clock pull-down circuit **325**. A slave latch **330** is coupled to the master latch **315** and is configured to receive a pair of complementary outputs from the master latch **315**. The slave latch **330** includes a slave clock pull-down circuit **335** coupled to a slave clock pull-up circuit **340**. The slave clock pull-up circuit **340** is configured to generate a slave latch output **385**. A data inverter **345** is configured to generate a flip-flop output **390** in response to the slave latch output **385**.

The operation of the flip-flop **300** illustrated in FIG. 3 is explained now. The multiplexer **305** receives a data input **355**, a scan data input **360**, a scan enable **365** and an inverted scan enable **370** and selects one of the data input **355** and the scan data input **360** in response to the scan enable **365**. The multiplexer output **375** is received at the inverter **310** and the inverted multiplexer output **380** is generated. The master latch **315** receives both the multiplexer output **375** and the inverted multiplexer output **380** at the master clock-pull up circuit **320**. The master clock pull-up circuit **320** generates a master first output (m2) **315a** and a master second output (m1) **315b** and is responsible for the implementation of the clock pull-up function in the master latch **315**. The master clock pull-down circuit **325** receives the master first output **315a** and the master second output **315b**. The master clock pull-down circuit **325** is responsible for generating the pair of complementary outputs which are then received at the slave latch **330** at the slave pull-down circuit **335**. The slave clock pull-down circuit **335** generates a slave first output (n8) **330a** and a slave second output (n7) **330b** and is responsible for the implementation of the clock pull-down function in the slave latch **330**. The slave clock pull-up circuit **340** receives the slave first output **330a** and the slave second output **330b** to generate the slave latch output **385**. The slave latch output **385** is inverted by the data inverter **345** to generate the flip-flop output **390**.

FIG. 4 illustrates a schematic of a transistor level implementation of a flip-flop **300** of FIG. 3. The flip-flop **400** is analogous to flip-flop **300** described in FIG. 3 in both connections and operations. The master clock pull-up circuit **320** includes a first tri-state inverter **320a** and a second tri-state inverter **320b**. The first tri-state inverter **320a** is configured to receive the multiplexer output **455** and in turn generates the master first output **425** to the master clock pull-down circuit **325**. Conventionally, a tri-state inverter can be implemented using an inverter coupled to a transmission gate, therefore the first tri-state inverter **320a** can be implemented as an inverter coupled to a transmission gate. A PMOS transistor **320a** (i) of the transmission gate is configured to receive the clock input **480** and an NMOS transistor **320a** (ii) of the transmission gate is configured to receive the master second output **430** of the

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master clock pull-up circuit **320**. The second tri-state inverter **320b** is configured to receive the inverted multiplexer output **460** and in turn generates the master second output **430** to the master clock pull-down circuit **325**. The second tri-state inverter **320b** can be further implemented using an inverter coupled to a transmission gate. A PMOS transistor **320b** (i) of the transmission gate is configured to receive the clock input **480** and an NMOS transistor **320b** (ii) of the transmission gate is configured to receive the master first output **425**. The master clock pull-down circuit **325** receives the master first output **425** and the master second output **430**. The master clock pull-down circuit **325** includes a first NMOS tri-stated inverter **325a** and a second NMOS tri-stated inverter **325b**. The first NMOS tri-stated inverter **325a** generates a first output in response to the master first output **425**. The second NMOS tri-stated inverter **325b** generates a second output in response to the master second output **430**. The first output and the second output are complementary to each other.

The first output and the second output from the master latch **315** are then received at the slave latch **330** at the slave pull-down circuit **335**. The slave pull-down circuit **335** includes a first tri-state inverter **335a** and a second tri-state inverter **335b**. The first tri-state inverter **335a** is configured to receive the second output from the master latch and in turn generates the slave first output **435** to the slave clock pull-up circuit **340**. The first tri-state inverter **335a** is implemented as an inverter coupled to a transmission gate. A PMOS transistor **335a** (i) of the transmission gate is configured to receive the slave second output **440** and an NMOS transistor **335a** (ii) of the transmission gate is configured to receive the clock input **480**. The second tri-state inverter **335b** is configured to receive the first output from the master latch and in turn generates the slave second output **440** to the slave clock pull-up circuit **340**. The second tri-state inverter **335b** can be further implemented using an inverter coupled to a transmission gate. A PMOS transistor **335b** (i) of the transmission gate is configured to receive the slave first output **435** and an NMOS transistor **335b** (ii) of the transmission gate is configured to receive the clock input **480**. The slave clock pull-up circuit **340** receives the slave first output **435** and the slave second output **440** to generate the slave latch output **445**. The slave clock pull-up circuit **340** includes a first PMOS tri-stated inverter **340a** and a second PMOS tri-stated inverter **340b**. The first PMOS tri-stated inverter **340a** receives the slave first output **435** of the slave clock pull-down circuit **335** and is configured to generate an output. The second PMOS tri-stated inverter **340b** is configured to generate the slave latch output **445** in response to the output generated by the first PMOS tri-stated inverter **340a**.

The operation of the flip-flop **400** illustrated in FIG. 4 is explained now. The multiplexer **305** selects either the data input **410** or the scan data input **415** in response to the scan enable **405**. The multiplexer output **455** is inverted by the inverter **310** to generate the inverted multiplexer output **460**. The master latch **315** receives the multiplexer output **455** and the inverted multiplexer output **460** and it is configured to generate the first output and the second output which are received at the slave latch **330**. The first output and the second output are complementary to each other. The master latch **315** and slave latch **330** are configured such that, there is no need of inverted clock input. The master clock pull-up circuit **320** receives the clock input **480** at the PMOS transistors (**320a**(i) and **320b**(i)) of the transmission gates of the first tri-state inverter **320a** and the second tri-state inverter **320b**. In the slave latch **330**, the clock input **480** is received at the NMOS transistors (**335a** (ii) and **335b** (ii)) of the transmission gates of the first tri-state inverter **335a** and the second tri-state

inverter **335b**. Thus, the inversion function is achieved by combination of the master clock pull-up circuit **320** and the slave pull-down circuit **335**. To maintain the robustness of the flip-flop **400**, a jam-latch' scenario is avoided. In other words the master latch **315** can be implemented using two back-to-back inverters, but in the flip-flop **400**, an input (the data input **410** and the scan data input **415**) is tri-stated with clock input **480** on the NMOS tri-stated inverters **325a** and **325b**. The NMOS tri-stated inverters **325a** and **325b** are used in order to avoid a conflict in logic of the input (data input **410** or scan data input **415**) that is being written into the master latch **315**. Similarly, in the slave latch **330** the PMOS tri-stated inverters **340a** and **340b** are used in order to avoid a conflict in logic of the input (data input **410** or scan data input **415**) that is being written into the slave latch **330**. Therefore, instead of using two back-to-back inverters, the master latch **315** and slave latch **330** receive complementary inputs and the complementary inputs are tri-stated using NMOS tri-stated inverters **325a** and **325b** and PMOS tri-stated inverters **340a** and **340b**, respectively. The complementary inputs are generated using the multiplexer **305** and inverter **310** at the master latch **315**. The second set of complementary inputs is generated by the master clock pull-down circuit **325** which is received by the slave latch **330**.

In several embodiments, the flip-flop **400** avoids the usage of an inverter to invert the clock input **480**, thereby reducing the power consumed by the toggling clock input. By eliminating the inverter, the flip-flop **400** is able to reduce the inverter short-circuit power loss. The need to align the flip-flop **400** to the clock input **480** no longer exists as in the case of flip-flop **100**. Further, the number of transistors that receive a constantly toggling signal is reduced from **10** transistors in flip-flop **100** to **8** transistors, thus eliminating the associated gate capacitances. The master latch **315** and slave latch **330** of the flip-flop **400** are not configured as jam-latches, hence the robustness of the flip-flop **400** is not compromised. In the flip-flop **400** greater transistor-stacking is achieved thereby resulting in significant savings in the leakage power as compared to the flip-flop **100**. As the flip-flop **300** is analogous to flip-flop **400** in connections and operations, the advantages discussed above apply to the flip-flop **300**.

FIG. **5** illustrates schematic of an apparatus using flip-flop **200** or flip flop **400** according to the embodiment. The apparatus **500** includes a clock input **505** and a plurality of flip-flops **510**. Each of the flip-flops of the plurality of flip-flops **510** is configured to receive the clock input **505**. Each flip-flop of the plurality of flip-flops **510** are analogous to flip-flop **200** or flip-flop **400** described in FIG. **2** and FIG. **4** respectively, in both connections and operations and thereby not repeated for the sake of simplicity. The flip-flops in the plurality of flip-flops **510** are configured to perform a combinational logic. An output **515** is generated at an output of the plurality of flip-flops **510**.

The apparatus **500** includes the large numbers of instantiated scan flip-flops **200**, hence with reduced transistor switching, the power consumed by the apparatus **500** can be significantly reduced. By eliminating an inverter (compared to a conventional apparatus) to invert the clock input **480**, the flip-flop **400** is able to reduce the inverter short-circuit power loss. The need to align the flip-flop **400** to the clock input **480** no longer exists as in the case of flip-flop **100**. Further the number of transistors that receive a constantly toggling signal is reduced from **10** transistors in flip-flop **100** to **8** transistors, thus eliminating the associated gate capacitances. In the flip-flop **400** greater transistor-stacking is achieved thereby resulting in significant savings in the leakage power as compared to the flip-flop **100**. Hence, with the reduction in the number gate

capacitances, leakage power and inverter short-circuit power loss, in each of the plurality of flip-flops **510**, a considerable amount of power is saved in the apparatus **500**.

FIG. **6** is a flowchart **600** illustrating a method of generating a flip-flop output **450** of a flip-flop **400**, according to an embodiment. The flip-flop **400** includes a multiplexer **305** and an inverter **310** coupled to the multiplexer **305**. The master latch **315** receives the multiplexer output **455** and the inverted multiplexer output **460**. The master latch **315** includes a master clock pull-up circuit **320** coupled to a master clock pull-down circuit **325**. A slave latch **330** is coupled to the master latch **315**. The slave latch **330** includes a slave clock pull-down circuit **335** coupled to a slave clock pull-up circuit **340** which generate a slave latch output **445**. A data inverter **345** is configured to generate a flip-flop output **450** in response to the slave latch output **445**.

At step **610**, the multiplexer **305** selects one of a data input **410** and a scan data input **415**, in response to a scan enable **415** to generate the multiplexer output **455**. At step **615**, the multiplexer output **455** is inverted by the inverter **310** to generate the inverted multiplexer output **460**. A master latch **315** is configured to receive a multiplexer output **455** and an inverted multiplexer output **460** from the multiplexer **305** and the inverter **310** respectively. At step **620**, the first output and the second output generated by the master latch **315** are received at the slave latch **330**. The slave latch output **445** is generated using the slave clock pull-down circuit **335** coupled to the slave clock pull-up circuit **340**, at step **625**. At step **630**, the slave latch output **445** is inverted by the data inverter **345** to generate the flip-flop output **450**. At step **635**, the flip-flop output **450** is generated without inverting the clock input **480**. The inversion of the clock input **480** is implemented through the steps **620** and **625**, as the clock input **480** pull-up is generated in step **620** and the clock input **480** pull-down is generated in step **625**.

The aforementioned method discloses a process of generating the flip-flop output **450** without using a separate inverter to invert the clock input **480**. By eliminating the inverter to invert the clock input **480**, the flip-flop **400** is able to reduce the inverter short-circuit power loss. The method eliminates the need to align the flip-flop **400** to the clock input **480** as in the case of flip-flop **100**. Further, the method describes steps to reduce the number of transistors that receive a constantly toggling signal, from **10** transistors in flip-flop **100** to **8** transistors, thus eliminating the associated gate capacitances. By following the steps described in flowchart **600** greater transistor-stacking is achieved that results in significant savings in the leakage power as compared to the flip-flop **100**. Thus a reduction in the number gate capacitances, leakage power and inverter short-circuit power loss is achieved.

In the foregoing discussion, the terms "connected" means at least either a direct electrical connection between the devices connected or an indirect connection through one or more passive intermediary devices. The term "circuit" means at least either a single component or a multiplicity of passive components, that are connected together to provide a desired function. The term "signal" means at least one current, voltage, charge, data, or other signal. Also, the terms "coupled to" or "couples with" (and the like) are intended to describe either an indirect or direct electrical connection. Thus, if a first device is coupled to a second device, that connection can be through a direct electrical connection, or through an indirect electrical connection via other devices and connections. Further, the term "high" is generally intended to describe a signal that is at logic state "1," and the term "low" is generally intended to describe a signal that is at logic state "0." The term "on" applied to a transistor or group of transistors is generally

intended to describe gate biasing to enable current flow through the transistor or transistors.

The foregoing description sets forth numerous specific details to convey a thorough understanding of the invention. However, it will be apparent to one skilled in the art that the invention may be practiced without these specific details. Well-known features are sometimes not described in detail in order to avoid obscuring the invention. Other variations and embodiments are possible in light of above teachings, and it is thus intended that the scope of invention not be limited by this Detailed Description, but only by the following Claims.

What is claimed is:

1. A flip-flop comprising:
  - a multiplexer configured to generate a multiplexer output to a transmission gate, in response to at least one input and a scan enable;
  - a master latch configured to receive an output of the transmission gate;
  - a tri-state inverter configured to receive an output of the master latch;
  - a slave latch configured to receive an output of the tri-state inverter and the multiplexer output;
  - a data inverter coupled to an output of the slave latch, configured to generate a flip-flop output; and
  - a half clock gating inverter configured to generate an inverted clock input in response to a clock input and the multiplexer output.
2. The flip-flop of claim 1, wherein the half clock gating inverter comprises:
  - an inverter having a first PMOS transistor and a first NMOS transistor, receiving the clock input to generate the inverted clock input;
  - a second PMOS transistor coupled to a source of the first PMOS transistor, a gate of the second PMOS transistor configured to be controlled by the multiplexer output; and
  - a second NMOS transistor coupled to a node between the drains of the first PMOS transistor and the first NMOS transistor, a gate of the second NMOS transistor configured to be controlled by the multiplexer output.
3. The flip-flop of claim 2, wherein:
  - the second PMOS transistor is activated and the second NMOS transistor is inactivated when the multiplexer output is logic '0', thereby generating the inverted clock input; and
  - the second PMOS transistor is inactivated and the second NMOS transistor is activated when the multiplexer output is logic '1', thereby tying the inverted clock input to logic '0'.
4. The flip-flop of claim 1, wherein the at least one input comprises a data input and a scan data input; and wherein, the multiplexer receives the data input, the scan data input, the scan enable and an inverted scan enable and is configured to select one of the data input and the scan data input in response to the scan enable.
5. The flip-flop of claim 1, wherein the master latch comprises a first plurality of back-to-back connected inverters and wherein, the first plurality of back-to-back connected inverters comprises an inverter coupled to a tri-state inverter.

6. The flip-flop of claim 1, wherein:
  - the slave latch comprises a second plurality of back-to-back connected inverters, wherein the second plurality of back-to-back connected inverters comprises a first inverter coupled to a second tri-state inverter;
  - the first inverter of the second plurality of back-to-back connected inverter is configured to generate an output to the data inverter; and
  - a third NMOS transistor coupled in parallel to an NMOS transistor of the second tri-state inverter, a gate of the third NMOS transistor receiving the multiplexer output, a gate of the NMOS transistor of the second tri-state inverter configured to receive the inverted clock.
7. The flip-flop of claim 6, wherein in the slave latch:
  - the third NMOS transistor is inactivated when the multiplexer output is logic '0'; and
  - the third NMOS transistor of the slave latch is configured to store the multiplexer output when the data input is logic '0' and the clock input is logic '0'.
8. The flip-flop of claim 1, wherein:
  - a data output is generated at the flip-flop output in a data state when the scan enable is logic '0'; and
  - a scan data output is generated at the flip-flop output in a scan state when the scan enable is logic '1'.
9. The flip-flop of claim 1, further comprising:
  - a scan inverter, configured to receive the scan enable to generate the inverted scan enable.
10. An apparatus comprising:
  - a clock input;
  - a plurality of flip-flops configured to receive the clock input; wherein each of the flip-flops comprises:
    - a multiplexer configured to generate a multiplexer output to a transmission gate, in response to an input and a scan enable;
    - a master latch configured to receive an output of the transmission gate;
    - a tri-state inverter configured to receive an output of the master latch;
    - a slave latch configured to receive an output of the tri-state inverter and the multiplexer output;
    - a data inverter coupled to an output of the slave latch, configured to generate a flip-flop output; and
    - a half clock gating inverter configured to generate an inverted clock input in response to the clock input and the multiplexer output; wherein the half clock gating inverter comprises:
      - a first PMOS and a first NMOS transistor, both configured to receive the clock input at gate terminal and configured to generate the inverted clock input;
      - a second PMOS transistor coupled to a source of the first PMOS transistor, the second PMOS transistor configured to be controlled by the multiplexer output; and
      - a second NMOS transistor coupled to a node between the drains of the first PMOS transistor and the first NMOS transistor, the second NMOS transistor configured to be controlled by the multiplexer output.

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